ON Semiconductor®



Assembly & Test site transfer of D2PAK products currently manufactured in ON Semiconductor		
Assembly & Test site transfer of D2PAK products currently manufactured in ON Semiconductor Cebu Philippines facility to ON Semiconductor Suzhou, China facility.		
07 Nov 2020 or earlier if approved by customer		
21 Jul 2020 Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.		
06 Nov 2020 The Current Material Last Delivery Date may be subject to change based on build and depletio of the current (unchanged) material inventory		
Active components – Discrete components		
Contact your local ON Semiconductor Sales Office or <peter.lee@onsemi.com></peter.lee@onsemi.com>		
Contact your local ON Semiconductor Sales Office to place sample order or <pcn.samples@onsemi.com>. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.</pcn.samples@onsemi.com>		
N/A		
N/A		
Contact your local ON Semiconductor Sales Office or Frank.Tuan@onsemi.com		
This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com.		
Type of Change		
Move of all or part of electrical wafer test and/or final test to a different location/site/subcontractor		
Production from a new equipment/tool which uses the same basic technology (replacement equipment or extension of existing equipment pool) without change of process.		
Move of all or part of assembly to a different location/site/subcontractor., Change of direct material supplier, Change of specified assembly process sequence (deletion and/or additional process step), Change of encapsulation/sealing material		
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Description and Purpose:

	Before Change Description	After Change Description	
LeadFrame Supplier	Hitachi(Single row)	TSP(Dual row)	
Mold Compound	MP195	KTMC5900GM	
Assembly Site	ON Cebu, Philiphines	ON Suzhou, China	
Test Site	ON Cebu, Philiphines	ON Suzhou, China	
Process flow(Plasma cleaning + AP coating)	No	Yes	



			From			То	
Product marking change					DN Semiconductor format assembly plant code change : 1		
or marking, The	ere is no change on the	device ma	arking for Suzhou. How	vever Suzhou will use the dif	erent Date cod	e which is ON	Format.
quipment in re	eceiving site may differe	ent with s	ending site, however a	all equipments are existing an	nd qualified in r	nass productic	on.
Reason / Motivation for Change: Capacit		ity improvement					
Anticipated impact on fit, form, s unction, reliability, product p afety or manufacturability:		success perform	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded.				
ites Affected	:	NO antio	cipated impacts.				
DN Semiconductor Sites				External Foundry/Subcon Sites			
N Semiconduc	tor Cebu, Philippines			None			
ON Semiconductor Suzhou, China							
		<u> </u>					
Narking of Pa hange: eliability Dat evice: FDB075 KG: D2PAK	-	onward	s once FPCN expire. Pa	rts from ON Semiconductor S arts from ON Semiconductor ON Semiconductor marking	Suzhou, China		
hange: eliability Dat evice: FDB075	a Summary: N15A-F085	onward product	s once FPCN expire. Pa	arts from ON Semiconductor	Suzhou, China		
hange: eliability Dat evice: FDB075 (G: D2PAK	a Summary:	onward product	s once FPCN expire. Pa	arts from ON Semiconductor ON Semiconductor marking Condition	Suzhou, China	can be identifi	ed through
hange: eliability Dat evice: FDB075 (G: D2PAK Test	a Summary: N15A-F085 Specification	onward product	s once FPCN expire. Pa marking which follow Tj = 150	arts from ON Semiconductor ON Semiconductor marking	Suzhou, China	can be identifi	ed through
nange: eliability Dat evice: FDB075 (G: D2PAK Test HTRB	a Summary: N15A-F085 Specification JESD22-A108	onward product	s once FPCN expire. Particular marking which follow Tj = 1500 Tj = 1500	arts from ON Semiconductor ON Semiconductor marking Condition C, Bias = 100% of rated BV	Suzhou, China	can be identifi Interval 1000hr	ed through Result 0/231
hange: eliability Dat evice: FDB075 KG: D2PAK Test HTRB HTRB HTGB	a Summary: N15A-F085 Specification JESD22-A108 JESD22-A108	onward product	s once FPCN expire. Particular follow marking which follow Tj = 150 Tj = 1500 MSL1, F	arts from ON Semiconductor ON Semiconductor marking Condition C, Bias = 100% of rated BV C, Bias = 100% of rated Vgs	Suzhou, China (format.	can be identifi Interval 1000hr	ed through Result 0/231 0/231
hange: eliability Dat evice: FDB075 KG: D2PAK Test HTRB HTGB PC	a Summary: N15A-F085 Specification JESD22-A108 JESD22-A108 J STD 020 , JESD22	A113	s once FPCN expire. Part marking which follow Tj = 1500 Tj = 1500 MSL1, F Temp = -55 100% C-SAM insp inspection or wire	arts from ON Semiconductor ON Semiconductor marking Condition C, Bias = 100% of rated BV C, Bias = 100% of rated Vgs eflow peak temp at 245C	Suzhou, China (format.	Interval 1000hr 1000hr	ed through Result 0/231 0/231 0/231
hange: eliability Dat evice: FDB075 KG: D2PAK Test HTRB HTRB HTGB PC TC + PC	a Summary: N15A-F085 Specification JESD22-A108 J STD 020 , JESD22 JESD22-A104 JESD22 A104; Q2	A113 035	s once FPCN expire. Particular marking which follow Tj = 1500 Tj = 1500 MSL1, F Temp = -55 100% C-SAM insp inspection or wire high	Condition Condition C, Bias = 100% of rated BV C, Bias = 100% of rated Vgs eflow peak temp at 245C C to +150°C, t(dwell>15 min pection after TC, follwed by d e pull on all wires from 5 part	Suzhou, China (format.	Interval 1000hr 1000hr	ed through Result 0/231 0/231 0/231 0/231 0/231
eliability Dat evice: FDB075 KG: D2PAK Test HTRB HTGB PC TC + PC TCDT	a Summary: N15A-F085 Specification JESD22-A108 JESD22-A108 J STD 020 , JESD22- JESD22-A104 JESD22 A104; Q2 appendix 6 J STD	A113 035	s once FPCN expire. Particular marking which follow Tj = 1500 Tj = 1500 MSL1, F Temp = -55 100% C-SAM insp inspection or wire high	Condition Condition C, Bias = 100% of rated BV C, Bias = 100% of rated Vgs eflow peak temp at 245C C to +150°C, t(dwell>15 min pection after TC, follwed by de pull on all wires from 5 part est delaminated parts.	Suzhou, China (format.	Interval 1000hr 1000cyc	ed through Result 0/231 0/231 0/231 0/231 0/231 0/266
hange: eliability Dat evice: FDB075 KG: D2PAK Test HTRB HTGB PC TC + PC TCDT HAST + PC	a Summary: N15A-F085 Specification JESD22-A108 JSTD 020 , JESD22- JESD22-A104 JESD22 A104; Q2 appendix 6 J STD JESD22-A110	A113 I01 035	s once FPCN expire. Particular marking which follow Tj = 1500 Tj = 1500 MSL1, F Temp = -55 100% C-SAM insp inspection or wire high	Condition Condition C, Bias = 100% of rated BV C, Bias = 100% of rated Vgs eflow peak temp at 245C C to +150°C, t(dwell>15 min pection after TC, follwed by d e pull on all wires from 5 part est delaminated parts. 35%RH, 110C, 42V	Suzhou, China (format.	Interval 1000hr 1000cyc 264hr	Result 0/231 0/231 0/231 0/231 0/231 0/231 0/66 0/231
hange: eliability Dat evice: FDB075 KG: D2PAK Test HTRB HTGB PC TC + PC TCDT HAST + PC UHAST + PC	a Summary: N15A-F085 Specification JESD22-A108 JESD22-A108 JSTD 020 , JESD22 JESD22-A104 JESD22 A104; Q2 appendix 6 J STD JESD22-A110 JESD22-A118	onward product	s once FPCN expire. Par marking which follow Tj = 1500 Tj = 1500 MSL1, F Temp = -55 100% C-SAM insp inspection or wire high Ta=25C Delta	Condition C, Bias = 100% of rated BV C, Bias = 100% of rated Vgs reflow peak temp at 245C C to +150°C, t(dwell>15 min pection after TC, follwed by de epull on all wires from 5 part est delaminated parts. 35%RH, 110C, 42V 85%RH, 110C	Suzhou, China (format.	Interval 1000hr 1000hr 1000cyc 264hr 264hr	ed through Result 0/231 0/231 0/231 0/231 0/231 0/66 0/231 0/231
hange: eliability Dat evice: FDB075 KG: D2PAK Test HTRB HTGB PC TC + PC TCDT HAST + PC UHAST + PC IOL	a Summary: N15A-F085 Specification JESD22-A108 JSTD 020 , JESD22- JESD22-A104 JESD22 A104; Q2 appendix 6 J STD JESD22-A110 JESD22-A110 MIL-STD-750 Metho	onward product	s once FPCN expire. Particular marking which follow Tj = 1500 Tj = 1500 MSL1, F Temp = -55 100% C-SAM insp inspection or wire high Ta=25C Delta Post H	Condition Condition C, Bias = 100% of rated BV C, Bias = 100% of rated Vgs eflow peak temp at 245C C to +150°C, t(dwell>15 min pection after TC, follwed by d e pull on all wires from 5 part est delaminated parts. 35%RH, 110C, 42V 85%RH, 110C Fj=100C°, t(on)=t(off)= 3.5 min	Suzhou, China o format.	Interval 1000hr 1000hr 1000cyc 264hr 264hr	Result 0/231 0/231 0/231 0/231 0/231 0/66 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231
hange: eliability Dat evice: FDB075 KG: D2PAK Test HTRB HTGB PC TC + PC TC + PC TCDT HAST + PC UHAST + PC IOL DPA	a Summary: N15A-F085 Specification JESD22-A108 JESD22-A108 JSTD 020 , JESD22 JESD22-A104 JESD22-A104; Q2 appendix 6 J STD JESD22-A110 JESD22-A110 JESD22-A118 MIL-STD-750 Metho AEC Q101-004 Sec	A113 -A113 -A113 d 1037 ction 4	s once FPCN expire. Particular marking which follow Tj = 1500 Tj = 1500 MSL1, F Temp = -55 100% C-SAM insp inspection or wire high Ta=25C Delta Post H Verify physic	Condition CON Semiconductor marking CN Semiconductor marking C, Bias = 100% of rated BV C, Bias = 100% of rated Vgs reflow peak temp at 245C C to +150°C, t(dwell>15 min pection after TC, follwed by de epull on all wires from 5 part est delaminated parts. 35%RH, 110C, 42V 85%RH, 110C Tj=100C°, t(on)=t(off)= 3.5 m H3TRB or HAST and TC	Suzhou, China o format.	Interval 1000hr 1000hr 1000cyc 264hr 264hr	Result 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231 0/231

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Note: AEC-1pager is attached.

To view attachments:

- 1. Download pdf copy of the PCN to your computer
- 2. Open the downloaded pdf copy of the PCN
- 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field
- 4. Then click on the attached file/s

Electrical Characteristics Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

Current Part Number	New Part Number	Qualification Vehicle
FDB2552-F085	NA	FDB075N15A-F085
FDB3632-F085	NA	FDB075N15A-F085
HUFA76645S3ST-F085	NA	FDB075N15A-F085
FDB3652-F085	NA	FDB075N15A-F085
FDB2532-F085	NA	FDB075N15A-F085
FDB14AN06LA0-F085	NA	FDB075N15A-F085
FDB070AN06A0-F085	NA	FDB075N15A-F085